

Deutsche Akkreditierungsstelle GmbH

Annex to the Accreditation Certificate D-PL-15047-01-00 according to DIN EN ISO/IEC 17025:2018

Valid from: 27.04.2022

Date of issue: 27.04.2022

Holder of certificate:

Gigahertz Optik GmbH
An der Kälberweide 12, 82299 Türkenfeld

Tests in the fields:

High frequency and radiation quantities

Optical quantities

- Photometry

- Radiometry

The testing laboratory is permitted, without being required to inform and obtain prior approval from DAkkS, to use standards or equivalent testing methods listed here with different issue dates.

The testing laboratory maintains a current list of all testing methods within the flexible scope of accreditation.

Technical field	Standard or test procedure / revision level	Title of standard or test method	Test method restrictions
Optics	CIE 220:2016	Characterization and Calibration Methods of UV Radiometers	Testing of narrow and Broad-Band radiometers in the

The management system requirements of DIN EN ISO/IEC 17025 are written in the language relevant to the operations of testing laboratories. Laboratories that conform to the requirements of this standard, operate generally in accordance with the principles of DIN EN ISO 9001.

The certificate together with the annex reflects the status as indicated by the date of issue.

The current status of any given scope of accreditation can be found in the directory of accredited bodies maintained by Deutsche Akkreditierungsstelle GmbH at <https://www.dakks.de/en/content/accredited-bodies-dakks>.

Abbreviations used: see last page

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This document is a translation. The definitive version is the original German annex to the accreditation certificate.

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Technical field	Standard or test procedure / revision level	Title of standard or test method	Test method restrictions
	ASTM G130-12 CIE 202:2011 DIN 5031-11:2009-02	Standard Test Method for Calibration of Narrow- and Broad-Band Ultraviolet Radiometers Using a Spectroradiometer Spectral responsivity measurement of detectors, radiometers and photometers Optical radiation physics and illuminating engineering - Part 11: Radiometer for measuring actinic radiant quantities - Terms, characteristics and their classification	wavelength range from 200 nm to 2500 nm
Optics	ASTM G0138-12	Standard Test Method for Calibration of a Spectroradiometer Using a Standard Source of Irradiance	Spectroradiometer / Device properties with defined settings / testing of the spectral irradiance in the wavelength range from 200 nm to 2500 nm
Optics	CIE 063:1984	The Spectroradiometric Measurement of Light Sources	Examination of the irradiance of lamps, luminaires and semiconductor light sources in the wavelength range from 200 nm to 2500 nm
Optics	CIE 210:2014	Photometry Using V(λ)-Corrected Detectors as Reference and Transfer Standards	Illuminance / Light measurement Photometer

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Optics	CIE 084:1989 DIN EN 13032-1:2012-06	The measurement of luminous flux Light and lighting - Measurement and presentation of photometric data of lamps and luminaires - Part 1: Measurement and file format; German version EN 13032-1:2004+A1:2012	Luminous flux from electrically operated spotlights / Measurement with an Ulbricht sphere using correction techniques / Measurement by integration of the illuminance distribution
Optik	CIE 127:2007	Measurement of LEDs	Luminous flux of LED / measurement with an Ulbricht sphere using correction techniques
Optik	CIE 063:1984	The Spectroradiometric Measurement of Light Sources	Spectral radiation flux (Radiant power) in the wavelength range from 350 nm to 1050 nm
Optik	CIE 063:1984 DIN EN 13032-1:2012-06	The Spectroradiometric Measurement of Light Sources Light and lighting - Measurement and presentation of photometric data of lamps and luminaires - Part 1: Measurement and file format; German version EN 13032-1:2004+A1:2012	Luminance and spectral radiance in the wavelength range from 250 nm to 2500 nm

Abbreviations used:

DIN Deutsches Institut für Normung e.V.
CIE Commission Internationale de L'Eclairage

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